Search Notes		

Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/630,833	EGUCHI ET AL.	
	Examiner	Art Unit	
	Thion E Tran	2011	

	SEAR	CHED	
Class	Subclass	Date	Examiner
257	340, 394	1/13/2005	TΤ
257	409, 488	1/13/2005	ΤΤ
257	630	1/13/2005	ΤT
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
257	340, 394	1/13/2005	ΤΤ
257	409, 488	1/13/2005	тт
257	630	1/13/2005	TT
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR